



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of: Suaya & Gabillet

Art Unit: 2858

Application No. 09/385,666

Filed: August 26, 1999

For: CAPACITANCE MEASUREMENTS FOR AN
INTEGRATED CIRCUIT

Examiner: Not yet assigned

Date: May 16, 2001

CERTIFICATE OF MAILING

I hereby certify that this paper and the documents referred to as being attached or enclosed herewith are being deposited with the United States Postal Service on May 16, 2001 as First Class Mail in an envelope addressed to: COMMISSIONER FOR PATENTS, WASHINGTON, D.C. 20231.

Attorney for Applicant

COMMISSIONER FOR PATENTS
WASHINGTON, D.C. 20231

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Technology Center 2100

PRELIMINARY AMENDMENT

Please amend the above-identified application as follows:

In the Drawings:

Please delete Figure 7 from the application.

In the Specification:

The following shows deletions to paragraphs and replacement paragraphs. A marked up version of the paragraphs being changed is attached to this amendment.

Please delete the paragraph on page 2, starting at line 15, and replace with the following clean paragraph:

Figure 1 represents the circuit 10 used in the IEEE paper to measure cross coupling capacitance. A general method to measure capacitance consists of measuring the total charge deposited on the capacitor, which can be accomplished by measuring DC currents, frequency of applied signals, and voltage. The following formula permits the determination of capacitance:

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01 FC:102
02 FC:103

80.00 OP
522.00 OP